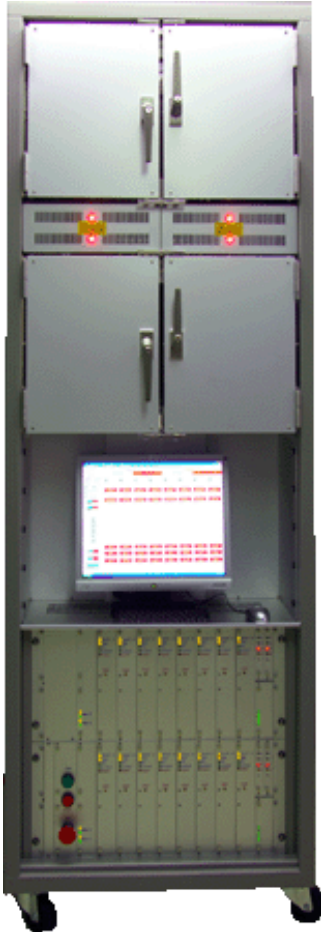


This test system fulfil requirements on HTRB systems for high voltage IGBT devices with high reverse power losses. This system is only HTRB equipment with continuous **measurement of junction temperature under bias voltage up to 2000V.**



Test capacity: 4 x 80 DUTs

Test chambers : 4

Temperature range : 50°C to 200°C per chamber

Test boards per chamber : 4

Possible voltage range : 0V to 1600V

0V to 2000V

Power supplies : Separate power supply for each test board

Calibration : Auto-calibration of each DUT before test

Test mode : Regulation of test temperatur after Tjunction

Regulation of test temperatur after Tcase

Sockets : Reliable device sockets designed for 200°C

Operating system : MS Windows XP

Handling : Comfortable graphic platform

Alarms : Programmable, light or sound

System controls : Continous for voltages and temperatures of chambers and test boards

DUT controls : Continous for bias voltages, leakage currents and juction temperatures with alarm and disconnection of test board by values over programmable limits